		Application/Control No.	Applicant(s)/Patent Under Reexamination
Notice of References Cited		10/025,932	LOPEZ ET AL.
		Examiner	Art Unit	Page 1 of 1
		Satish S. Rampuria	2124	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0174174 A1	11-2002	Ramraj et al.	709/203
*	B	US-2002/0046273 A1	04-2002	Lahr et al.	709/224
*	C	US-6,687,702 B2	02-2004	Vaitheeswaran et al.	707/10
*	D	US-6,654,949 B1	11-2003	Fraenkel et al.	717/130
*	E	US-6,698,013 B1	02-2004	Bertero et al.	717/127
*	F	US-2003/0066059 A1	04-2003	Moon et al.	717/148
*	G	US-6,647,544 B1	11-2003	Ryman et al.	717/124
*	H	US-2004/0107415 A1	06-2004	Melamed et al.	717/124
*	I	US-2004/0107415 A1	06-2004	Melamed et al.	717/124
*	J	US-2001/0054026 A1	12-2001	Choate, Timothy	705/52
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Xiaoping et al., A generic approach of static analysis for detecting runtime errors in Java programs, 27-29 Oct. 1999, IEEE, Pages:67 - 72
	V	Al-Theyeyan et al., XML-based visual specification of multidisciplinary applications, 15-18 May 2001, IEEE, Pages:414 - 421
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.